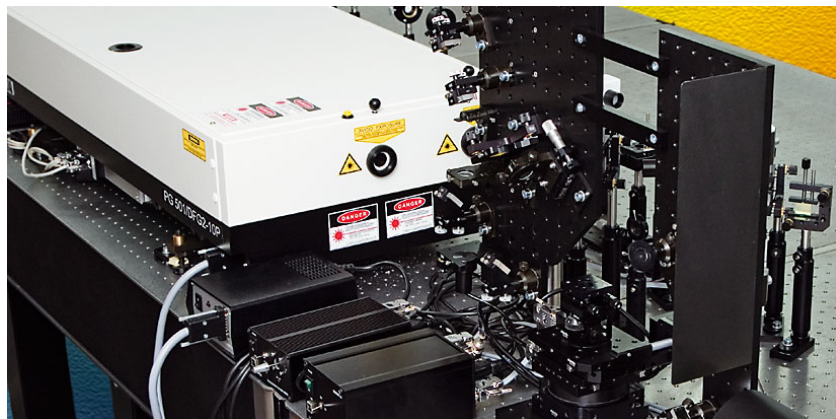


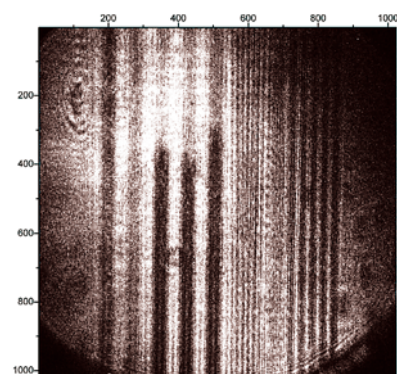
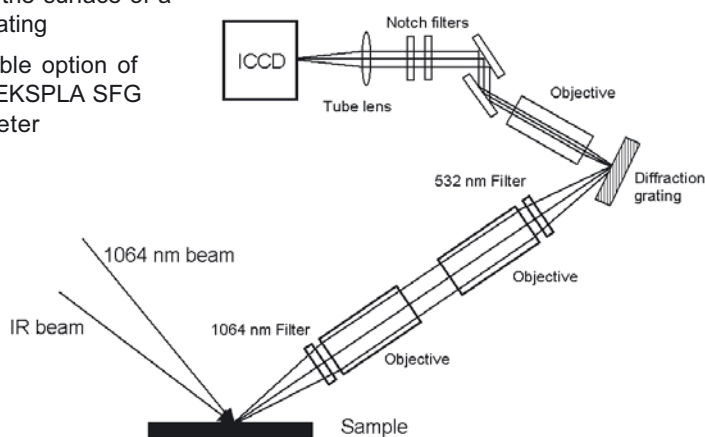
SFG MICROSCOPE

Sum Frequency Generation (SFG) Imaging Microscope



DESIGN

- Far field imaging
- Detection via an intermediate image on the surface of a blazed grating
- Upgradeable option of standard EKSPLA SFG spectrometer



An image of ODT covered etched gold sample. The lines are spaced, in order left-right 20, 5, 2, and 8 micrometers. Image taken at $\omega_{IR}=2875 \text{ cm}^{-1}$ and acquired for 5000 laser shots.

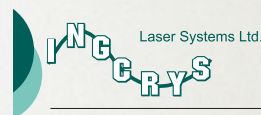
SPECIFICATIONS

Resolution	< 5 μm
Field of view	300 μm
Magnification	20
VIS beam wavelength	1064.2 nm
IR wavelength range	2000 – 3800 cm^{-1}
CCD	Roper Scientific ICCD 1024X1024

ADVANTAGES

- High interface specificity
- Monolayer sensitivity
- Chemical contrast
- Structural information
- Spatial distribution
- Answering questions of sample inhomogeneity

EKSPLA distributor in United Kingdom:



Ingcrys Laser Systems Ltd
14 Parris Road, Stokenchurch,
High Wycombe, Bucks. UK
Tel.: + 44 (0) 1494 482541
Fax: + 44 (0) 1494 482873
Email: sales@ingcrys.com
www.ingcrys.com

Lasers and Laser Systems Div.
Savanoriu av. 231
02300 Vilnius – 53
L I T H U A N I A

Ph.: +370 5 2649629
Fax: +370 5 2641809
sales@ekspla.com
www.ekspla.com